

FDS8926A

Dual N-Channel Enhancement Mode Field Effect Transistor

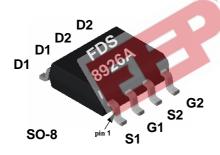
General Description

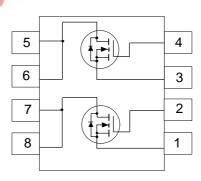
SO-8 N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to provide superior switching performance and minimize on-state resistance. These devices are particularly suited for low voltage applications such as disk drive motor control, battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.

Features

- = 5.5 A, 30 V. $R_{\rm DS(ON)}$ = 0.030 Ω @ $V_{\rm GS}$ = 4.5 V $R_{\rm DS(ON)}$ = 0.038 Ω @ $V_{\rm GS}$ = 2.5 V.
- High density cell design for extremely low R_{DS(ON)}.
- Combines low gate threshold (fully enhanced at 2.5V) with high breakdown voltage of 30 V.
- High power and current handling capability in a widely used surface mount package.
- Dual MOSFET in surface mount package.







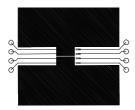
Absolute Maximum Ratings $T_A = 25^{\circ}C$ unless other wise noted

Symbol	Parameter	FDS8926A	Units
V _{DSS}	Drain-Source Voltage	30	V
V _{GSS}	Gate-Source Voltage	±8	V
I _D	Drain Current - Continuous (Note 1a)	5.5	А
	- Pulsed	20	
P _D	Power Dissipation for Dual Operation	2	W
	Power Dissipation for Single Operation (Note 1a)	1.6	
	(Note 1b)	1	
	(Note 1c)	0.9	
T _J ,T _{STG}	Operating and Storage Temperature Range	-55 to 150	°C
THERMA	L CHARACTERISTICS		·
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	78	°C/W
R _{euc}	Thermal Resistance, Junction-to-Case (Note 1)	40	°C/W

Symbol	Parameter	Conditions	Min	Тур	Max	Units
OFF CHAR	ACTERISTICS	•				
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	30			V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient	I _D = 250 μA, Referenced to 25°C		32		mV/°C
DSS	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \ V_{GS} = 0 \text{ V}$			1	μΑ
		T _J = 55°C			10	μA
GSSF	Gate - Body Leakage, Forward	V _{GS} = 8 V, V _{DS} = 0 V			100	nA
GSSR	Gate - Body Leakage, Reverse	$V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
	CTERISTICS (Note 2)		•	•		
/ _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	0.4	0.67	1	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Temp. Coefficient	I _D = 250 μA, Referenced to 25°C		-3		mV /°C
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 5.5 \text{ A}$		0.025	0.03	Ω
,		T _J =125°C		0.037	0.052	
		$V_{GS} = 2.5 \text{ V}, I_D = 4.5 \text{ A}$		0.031	0.038	
(ON)	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, \ V_{DS} = 5 \text{ V}$	20			Α
FS	Forward Transconductance	$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$ $V_{DS} = 5 \text{ V}, I_{D} = 5.5 \text{ A}$ $V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$		20		S
YNAMIC	CH ARACTERISTICS	2 %	U .			
'iss	Input Capacitance	$V_{DS} = 10 \text{ V}, \ V_{GS} = 0 \text{ V},$		900		pF
oss	Output Capacitance	f = 1.0 MHz		410		pF
rss	Reverse Transfer Capacitance			110		pF
WITCHING	CHARACTERISTICS (Note 2)					
O(on)	Turn - On Delay Time	$V_{DS} = 6 \text{ V}, I_{D} = 1 \text{ A}$		6	12	ns
	Turn - On Rise Time	$V_{GS} = 4.5 \text{ V}$, $R_{GEN} = 6 \Omega$		19	31	
(off)	Turn - Off Delay Time			42	67	
	Turn - Off Fall Time			13	24	
Q_g	Total Gate Charge	$V_{DS} = 10 \text{ V}, I_{D} = 5.5 \text{ A},$		19.8	28	nC
Q_{gs}	Gate-Source Charge	V _{GS} = 4.5 V		2		
\mathbf{Q}_{gd}	Gate-Drain Charge			6.3		
RAIN-SOL	IRCE DIODE CHARACTERISTICS AND MAX	IMUM RATINGS				
3	Maximum Continuous Drain-Source Diode Forward Current				1.3	Α
/ _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 1.3 \text{ A} \text{ (Note 2)}$		0.68	1.2	V

Notes:

1. R_{g,M} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{g,C} is guaranteed by design while $\boldsymbol{R}_{\scriptscriptstyle \theta \text{CA}}$ is determined by the user's board design.







Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2.0%.

Typical Electrical Characteristics

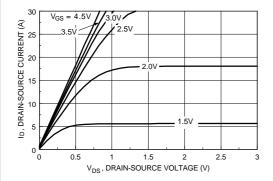


Figure 1. On-Region Characteristics.

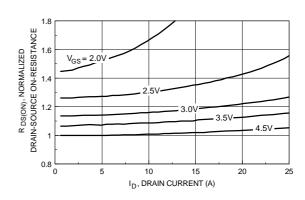


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

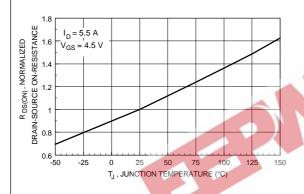


Figure 3. On-Resistance Variation With Temperature.

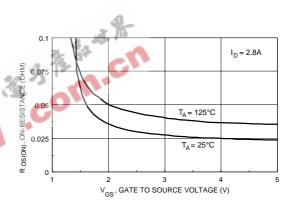


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

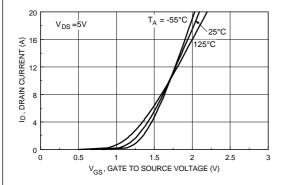


Figure 5. Transfer Characteristics.

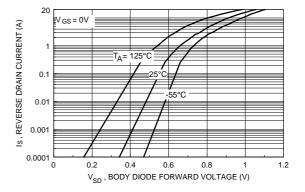
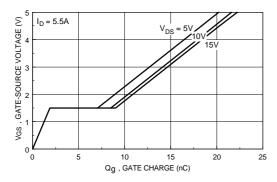


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Electrical And Thermal Characteristics



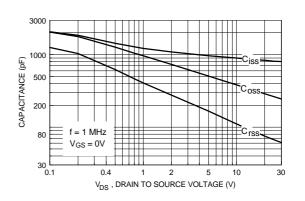
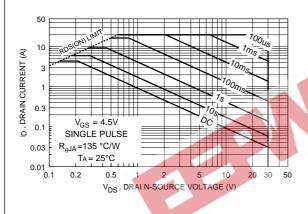


Figure 7. Gate Charge Characteristics.





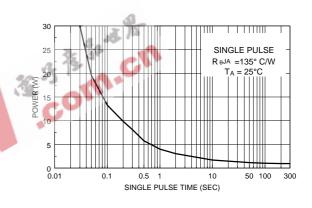


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

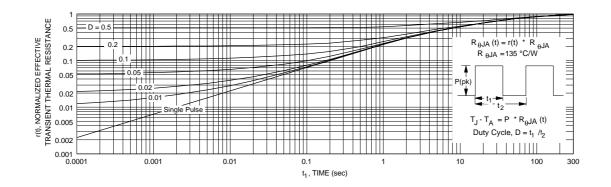
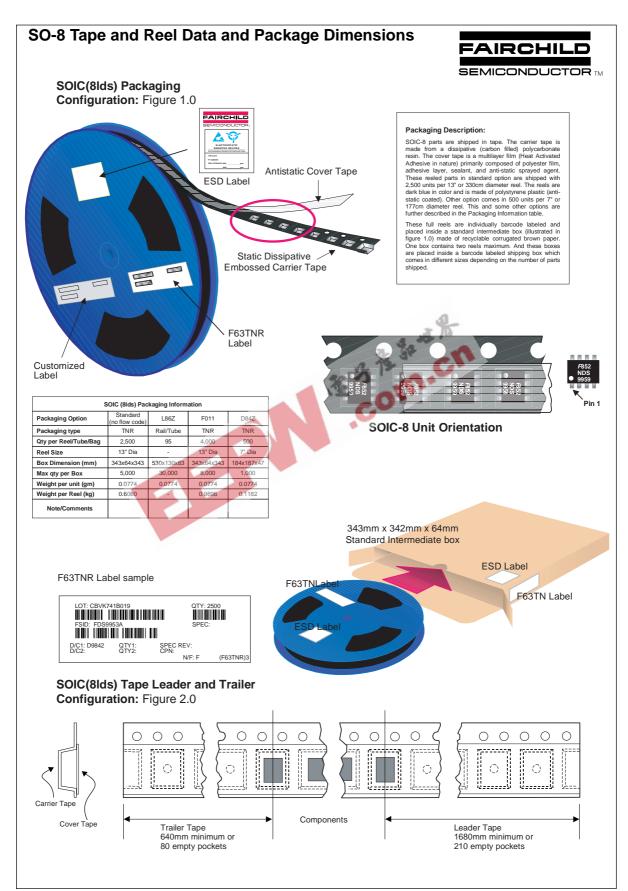
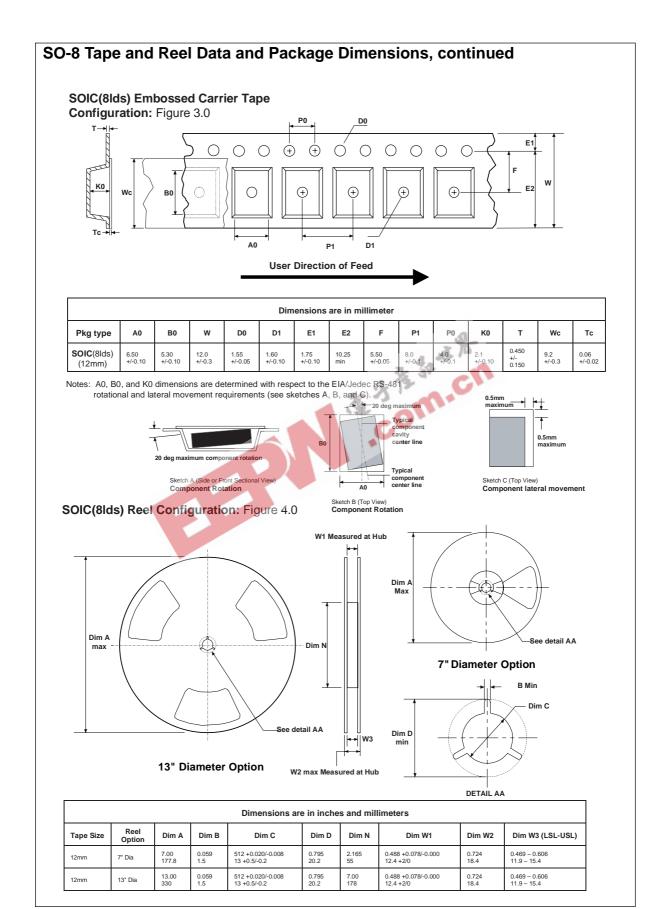
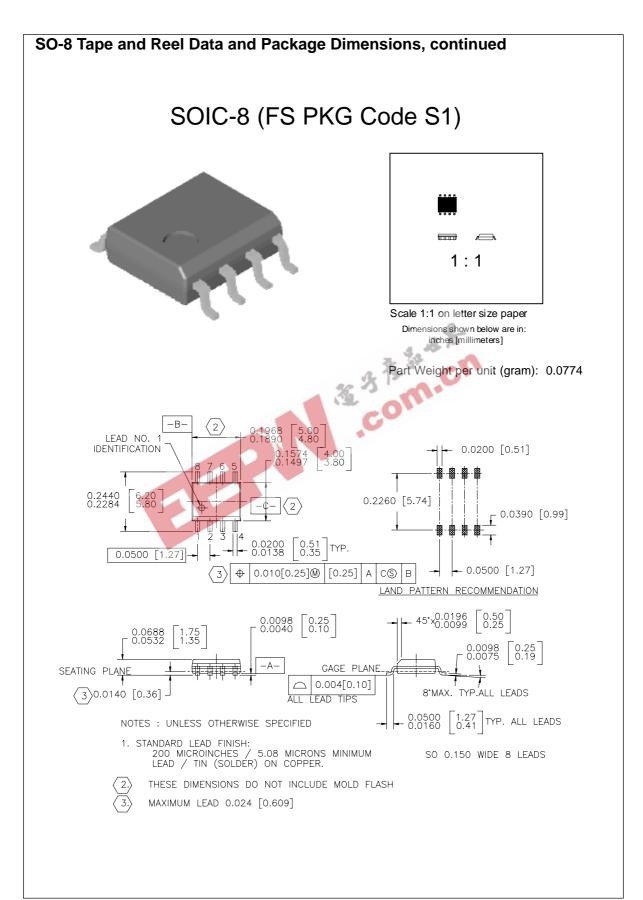


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.







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